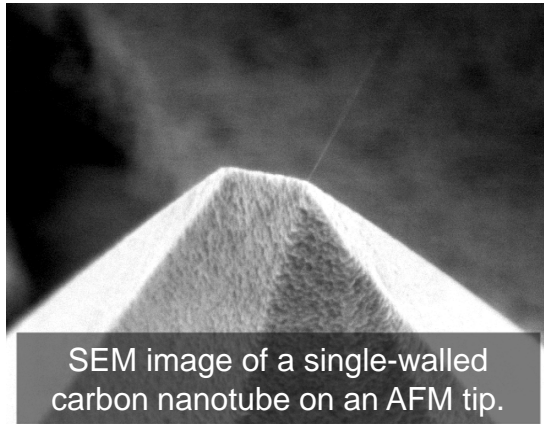


Carbon Nanotube Atomic Force Microscope Tip

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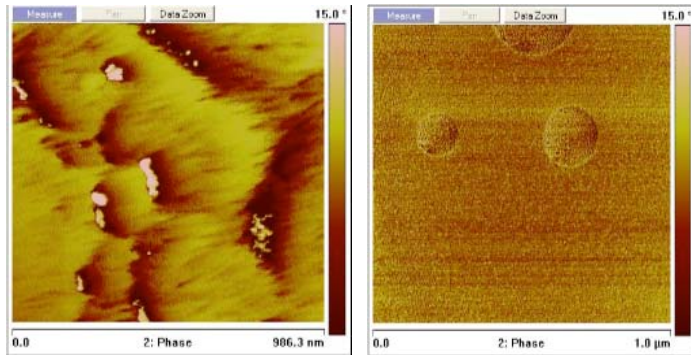


SEM image of a single-walled carbon nanotube on an AFM tip.

Attaching Single-Walled Carbon Nanotubes (SWCNT's) to the end of an Atomic Force Microscope probe creates the sharpest possible tip and enables the user to analyze soft structures, such as proteins. This will allow the analysis of small scale structures in the semiconductor industry as well as to help reduce the cost of drug discovery.

Carbon Nanoprobes has been working with the Penn State NNIN Site to develop scalable processes for producing SWCNT-tipped AFM probes.

Carbon Nanoprobes maintains a growing patent portfolio in the nanotechnology and molecular imaging space that has benefited from this interaction.



Details evident using CNT tipped AFM probe (left) are not present using Si AFM tip (right).

Penn State Site